



Title of Change:	Qualification of Die Technology Change from Open Junction Technology to Glass Passivation Technology for Standard Recovery Diode.							
Proposed first ship date:	15 June 2018 Or earlier after customer approval							
Contact information:	Contact your local ON Semiconductor Sales Office or <norsahida.sahman@onsemi.com>							
Samples:	Contact your local ON Semiconductor Sales Office							
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or < Lalan.Ortega@onsemi.com>							
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.							
Change Part Identification:	There will be no change in device marking scheme. Clean date code will be advised later.							
Change category:	<input type="checkbox"/> Wafer Fab Change <input checked="" type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____							
Change Sub-Category(s):	<input checked="" type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____							
Sites Affected:	ON Semiconductor Sites: None	External Foundry/Subcon Sites: SuZhou Good-Ark Electronics Co. Ltd.						
Description and Purpose:								
<p>This is a Final Product Change Notification announcing to customers that ON Semiconductor is qualifying glass passivated technology on Standard Recovery Diode.</p> <p>This change is being driven by tightening environmental restrictions. This situation has forced the discontinuation of the OJR production. Life time buys of OJR product will not be possible thus the equivalent glass passivated devices will be offered.</p> <table border="1"> <thead> <tr> <th></th> <th>Before Change Description</th> <th>After Change Description</th> </tr> </thead> <tbody> <tr> <td>Die</td> <td>Open junction technology</td> <td>Glass passivation technology</td> </tr> </tbody> </table> <p>The glass passivated devices will be using qualified BOM in assembly. There will be no change In part marking and part numbering. The GPP replacements will be qualified to commercial/industrial requirements. These devices are not qualified to automotive standards and are not recommended for automotive applications.</p>				Before Change Description	After Change Description	Die	Open junction technology	Glass passivation technology
	Before Change Description	After Change Description						
Die	Open junction technology	Glass passivation technology						

**Reliability Data Summary:**QV DEVICE NAME: 1N5408RLGRMS: S42890, S43656PACKAGE: DO201AD

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0 / 240
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0 / 240
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15,000 cyc	0 / 80
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0 / 240
AC	JESD22-A102	Ta = 121°C, RH = 100%, 15psig	96 hours	0 / 240
H3TRB	JESD22-A101	Ta = 85°C/85% RH, 80% max rated V	1008 hrs	0 / 239
RSH	JESD22- B106	Ta = 265C, 10 sec		0 / 30

Electrical Characteristic Summary:

Electrical characteristics are not impacted

List of Affected Standard Parts:

Part Number	Qualification Vehicle
1N5400G	1N5408RLG
1N5400RLG	
1N5401G	
1N5401RLG	
1N5402G	
1N5402RLG	
1N5404G	
1N5404RLG	
1N5406G	
1N5406RLG	
1N5407G	
1N5407RLG	
1N5408G	
1N5408RLG	
SR5401ARLG	